

*Ultrathin Alumina Passivation for Improved Photoelectrochemical Water Oxidation Catalysis of Tin Oxide Sensitized by a Phosphonate-Functionalized Perylene Diimide First Without, and then With,  $CoO_y$*

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## **Table of Contents:**

### **S1. Experimental Details for the Atomic Layer Deposition of AlO<sub>x</sub>**

**Table S1:** Ellipsometry measurements of AlO<sub>x</sub> by ALD

**Figure S1:** Plot of ellipsometry measurements of AlO<sub>x</sub> by ALD

### **S2. UV-vis Spectra of Anodes with and without AlO<sub>x</sub>**

**Figure S2:** Absorbance and Absorptance Spectra of Anodes

### **S3. Photocorrosion Controls on SnO<sub>2</sub>/PMPDI/AlO<sub>x</sub>/CoO<sub>y</sub>**

### **S4. AlO<sub>x</sub> Photoactivity, Disproof of WOCatalyst Character**

**Figure S3:** Photoelectrochemistry of AlO<sub>x</sub>

### **S5. High Resolution XPS of AlO<sub>x</sub>**

**Figure S4:** Representative high resolution XPS scan Al 2 p electron

### **S6. Thermogravimetric Analysis of PMPDI Stability**

**Figure S5:** TGA of PMPDI

### **S7. SEM Image of Anodes**

**Figure S6:** SEM of SnO<sub>2</sub>/PMPDI/AlO<sub>x</sub> (0.6 nm, 85 °C) anode

### **S8. Photocurrent Measurement of Optimized Anode for Decay:**

**Figure S7:** i-t for SnO<sub>2</sub>/PMPDI/AlO<sub>x</sub>/CoO<sub>y</sub> (0.6 nm, 85 °C deposition) for decay

### **S9. Experimental Details for SnO<sub>2</sub>/AlO<sub>x</sub>/PMPDI System**

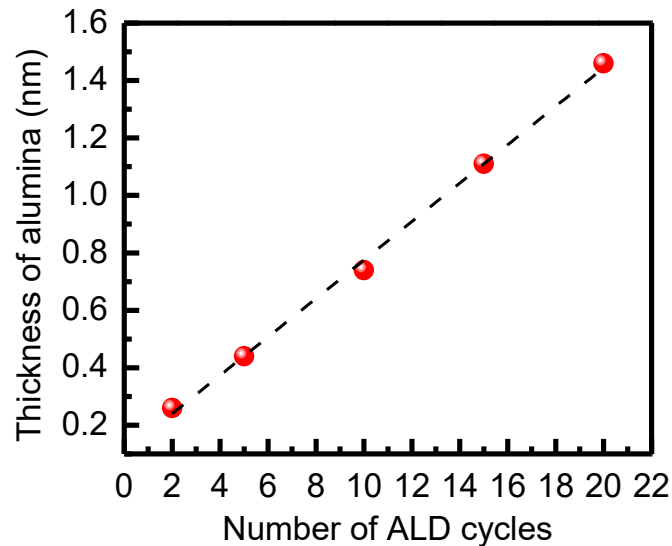
## S1. Experimental Details for the Atomic Layer Deposition of AlO<sub>x</sub>

### Ellipsometry Measurement.

To determine the alumina film thickness, the spectral reflectance of Si wafers coated with varying numbers of alumina ALD cycles was measured by a J.A. Woollam M-2000FI ellipsometer. The spectral reflectance data were collected and analyzed using the WVASE32 data acquisition and analysis software (J.A. Woollam Co. Inc.). The incidence angle of the light beam was varied from 50° to 80° with an angle step size of 5°, normal to the substrate plane. The reflectance data were collected over the wavelengths ranging from 200 to 1600 nm. The alumina film thickness was determined by fitting the collected data to a three-layer model (Al<sub>2</sub>O<sub>3</sub>/native SiO<sub>2</sub>/Si) using the known optical constants of the materials available in the software.

**Table S1:** Results of alumina measured by ellipsometry as a function of the number of ALD cycles

Number of ALD cycles	Thickness of AlO <sub>x</sub> (nm)
2	0.26
5	0.44
10	0.74
15	1.11
20	1.46

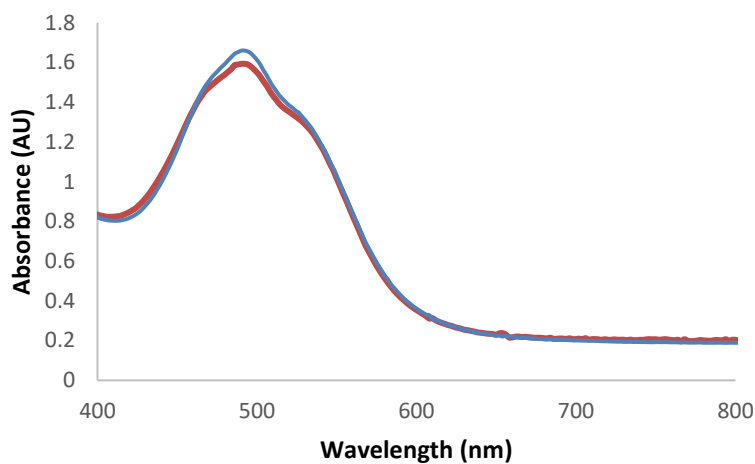


**Figure S1:** Thickness of alumina measured by ellipsometry as a function of the number of ALD cycles

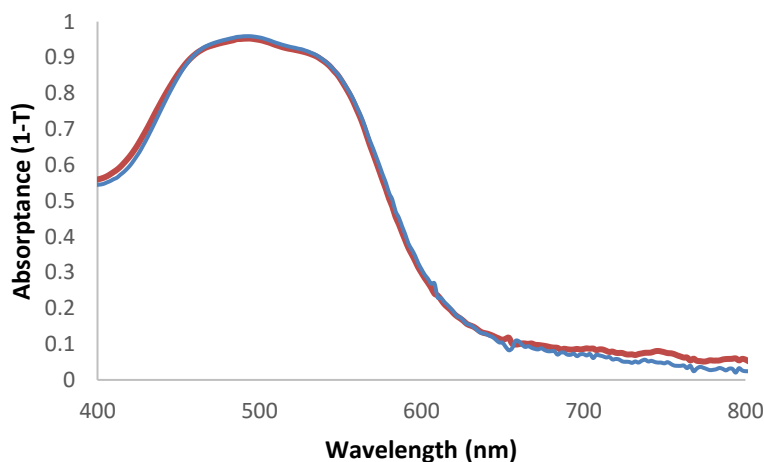
## S2. UV-vis Spectra of Anodes with and without AlO<sub>x</sub>

Using a Hewlett Packard 8452A diode array spectrophotometer, UV-vis data were collected on anodes. Anodes were placed directly against the back wall for consistency and a cleaned FTO slide was used as the reference blank.

a.



b.



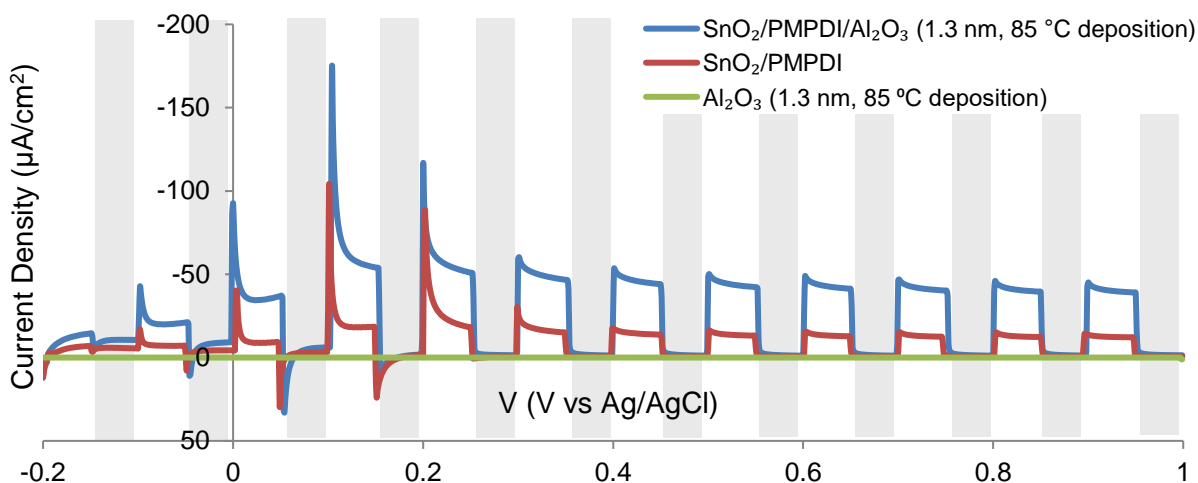
**Figure S2:** Absorbance (a) and absorbance (b) plot for SnO<sub>2</sub>/PMPDI (red) and SnO<sub>2</sub>/PMPDI/AlO<sub>x</sub> (1.3 nm, 85 °C deposition, blue) anodes. Both the degree to which the dye and SnO<sub>2</sub> absorb light as well as the  $\lambda_{\text{max}}$  and absorbance pattern remain unchanged after alumina deposition. The UV-Vis of the anode before and after the ALD indicate the bond between the SnO<sub>2</sub> and the dye was unchanged with the addition of AlO<sub>x</sub> at elevated temperatures.

### **S3. Photocorrosion Controls on SnO<sub>2</sub>/PMPDI/AlO<sub>x</sub>/CoO<sub>y</sub>**

Hydroquinone (H<sub>2</sub>Q) was added to the system to examine the anode using a more thermodynamically and kinetically facile reaction. An interesting feature of the photocurrent transient data is the spiking behavior. With the addition of H<sub>2</sub>Q, a significant decrease in spiking behavior was observed, and the kinetics of the system appear to be shifted in such a way that the recombination is minimized. Our current leading hypothesis for these large spikes at particularly ca. +0.1 V vs Ag/AgCl is photocorrosion, but SnO<sub>2</sub> impurities are certainly another hypothesis. Of note, the conduction band edge for SnO<sub>2</sub> is also in the region of high spiking behavior.<sup>1</sup> This may suggest that there is some photocorrosion occurring due to hole accumulation in the system doing water oxidation, but with the easier oxidation reaction, this can be surmounted.

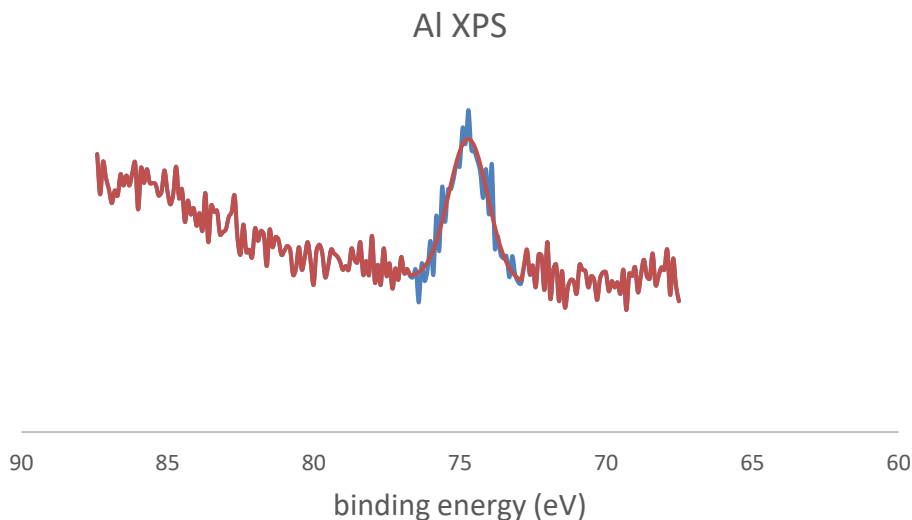
Another interesting feature seen in photocurrent transient plots is an increased steady-state value at +0.1 to +0.2 V vs Ag/AgCl. We currently have not determined the origin of this feature but favor some combination of photocorrosion, degradation, non-water oxidation faradaic processes, or electrochemical processes relating to the SnO<sub>2</sub>. We hypothesize that the defects and impurities in our SnO<sub>2</sub> may be related to this feature. As such, SnO<sub>2</sub> by ALD is of great interest to us and future work will explore this hypothesis.

### **S4. AlO<sub>x</sub> Photoactivity, Disproof of WOCatalyst Character**



**Figure S3:** Photocurrent transients (with 5 s light/dark transients indicated by white/ gray shading) for SnO<sub>2</sub>/PMPDI/AlO<sub>x</sub> anodes (1.3 nm, 85 °C deposition, blue), SnO<sub>2</sub>/AlO<sub>x</sub> (1.3 nm, 85 °C deposition, red), and AlO<sub>x</sub> (1.3 nm, 85 °C deposition, green). Scans were done from -0.2 to +1.0 V vs Ag/AgCl with 5 second light, then dark transients. Examining the photocurrents, combined with the negligible oxygen production in the latter two cases, indicates that alumina is not functioning as a WOC.

## **S5. High Resolution XPS of AlO<sub>x</sub>**



**Figure S4:** Representative high resolution XPS scan Al 2 p electron on alumina as deposited at 85 °C

XPS was carried out inhouse on a PE-5800 series Multi-Technique ESCA XPS system where a Al K $\alpha$  monochromatic source operating at 350.0 W was used for all XPS experiments. High resolution (HRES) scans were carried out at a minimum of 3 spots across the sample surface for 30 minutes apiece. To fit the data, CASAXPS software was used to analyze the data. Consistent with both the literature method of XPS fitting and ensuring self-consistency across fits, HRES spectra were calibrated to a 285 eV aliphatic carbon peak.<sup>2,3</sup>

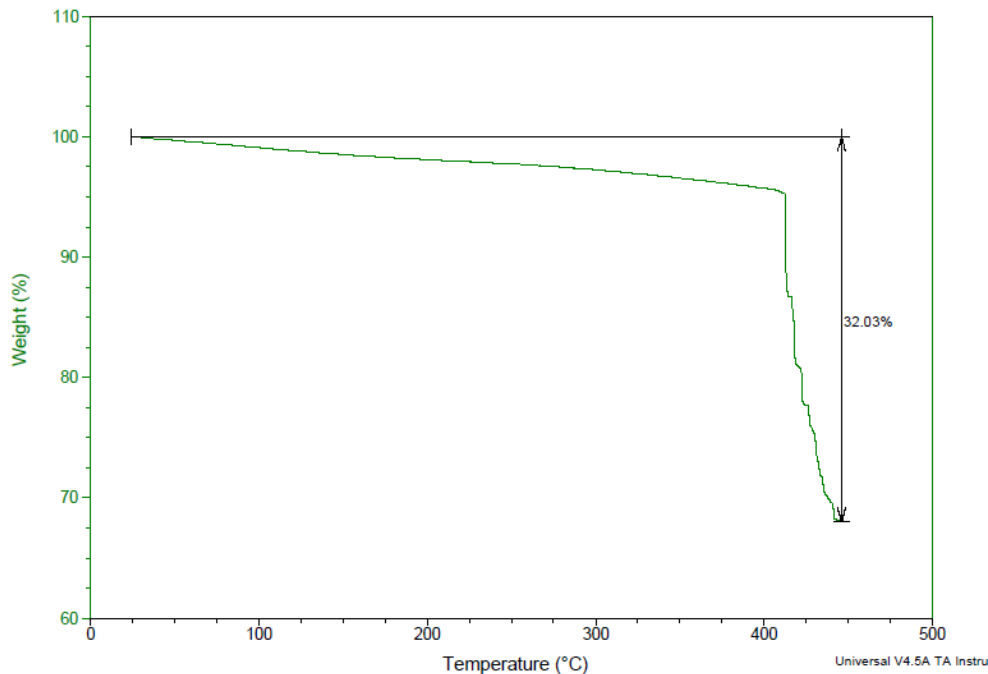
XPS was carried out on a sample of AlO<sub>x</sub> deposited at 85 °C. XPS detected only one Al environment, corresponding to the oxide (Figure S4). O deficiencies, which would appear as a peak at a lower binding energy, can certainly impact the conductivity of the alumina layer. However, in all cases one alumina oxide environment was seen and an O deficiency peak is not present.

Of note, cobalt was not visible by XPS even during extended high resolution scans due to the very low, catalytic quantities used.

## **S6. Thermogravimetric Analysis of PMPDI Stability**

To probe the hypothesis that the PMPDI dye was being degraded under the temperatures used for ALD, a control of thermogravimetric analysis of the dye was done. Though the relatively high thermal stability for an organic compound and dye is one of the primary reasons PDI organic dyes are of interest and used in the present work and other devices, this hypothesis was still investigated. TGA was done using a TA Instruments TGA 2950 Thermogravimetric Analyzer under air flow

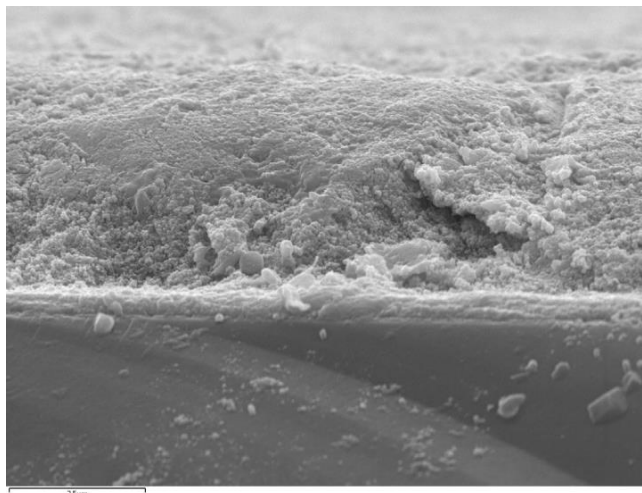
and using a 20 °C/min heating ramp rate (Figure S5). The TGA shows that the dye is stable up to 400 °C, fully consistent with the general literature of PDI dye stability to approximately 300–600 °C.<sup>4</sup>



**Figure S5.** TGA of powder PMPDI from 25–450 °C, ramping 20 °C/minute, and under ambient atmosphere conditions. With increasing temperature, there is minimal weight loss up to 400 °C, indicating PMPDI is stable up to 400 °C. This means all AlO<sub>x</sub> depositions herein, ranging from 85 °C to 200 °C, do not cause the PMPDI dye to thermally degrade.

### **S7. SEM Image of Anodes**

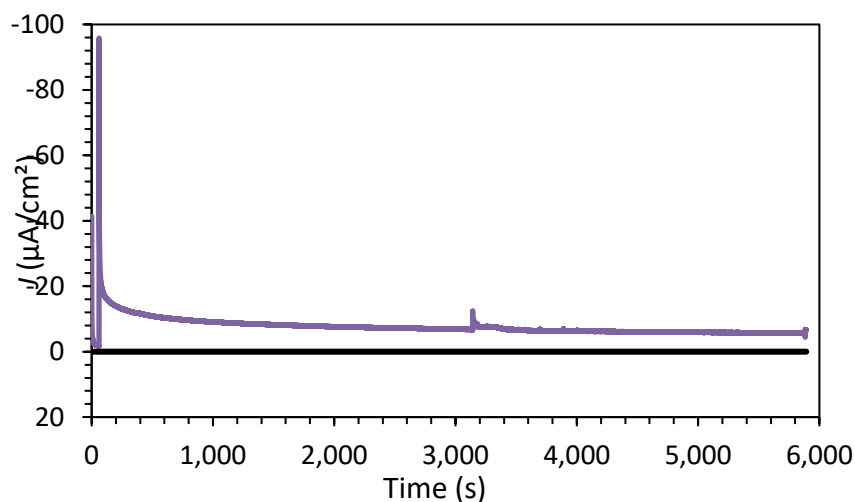
Scanning electron microscopy (SEM) images were taken for SnO<sub>2</sub>/PMPDI/AlO<sub>x</sub> (0.6 nm, 85 °C deposition) anodes to ensure film morphology remained comparable to previously published SEM images of films without alumina.<sup>1</sup> Images were collected using a JEOL JSM-6500F field emission scanning electron microscope (FESEM), using 15 kV accelerating voltage and 10 mm working distance. Porosity in films was observed.



**Figure S6:** SEM image of  $\text{SnO}_2/\text{PMPDI}/\text{AlO}_x$  (0.6 nm, 85 °C)/ $\text{CoO}_y$  anode taken at 30,000X magnification. Image is a profile of the cross section of the anode after cracking. The FTO glass is clearly visible at the bottom of the SEM image of the cross section for reference and perspective.

SEM-EDS (energy dispersive X-ray spectrometer) data were collected using an Oxford Instruments energy dispersive X-ray spectrometer and Oxford Aztec software was used for qualitative and quantitative elemental analysis. A  $\text{SnO}_2/\text{PMPDI}/\text{AlO}_x$  (0.6 nm, 85 °C)/ $\text{CoO}_y$  anode was cracked in half in order to examine the cross section (Figure S6). The anode was then coated in 10 nm of gold. The cross section of the anode was then examined using SEM-EDS, though the sample had to be oriented at a slight angle off of vertical, in order to determine if cobalt was seen throughout the sample. Cobalt was not detected due to the very low, catalytic quantity used.

### **S8. Photocurrent Measurement for Optimized Anode for Decay:**



**Figure S7:** i-t of a representative  $\text{SnO}_2/\text{PMPDI}/\text{AlO}_x/\text{CoO}_y$  (0.6 nm, 85 °C deposition) anode performed at +0.2 V vs Ag/AgCl in pH 7, 0.1 M KPi buffer. Measurements were taken for over 90 minutes to look at photocurrent decay.



In order to understand the longevity of the photoanode system, the photocurrent of a representative SnO<sub>2</sub>/PMPDI/AlO<sub>x</sub> (0.6 nm, 85 °C deposition)/CoO<sub>y</sub> anode was measured at +0.2 V vs Ag/AgCl. In an extended, ca. 1.5 hour long, experiment, a significant, 78%, decay in photocurrent generation was noted. Replicate O<sub>2</sub> detection experiments displayed a decay of O<sub>2</sub> evolution by 11% after four replicate trials (1200 s).

### **S9. Experimental Details for SnO<sub>2</sub>/AlO<sub>x</sub>/PMPDI System**

Deposition of AlO<sub>x</sub> was also done on the nano-SnO<sub>2</sub> rather than the SnO<sub>2</sub>/PMPDI in order to determine if a more optimal placement of the layer could be achieved. Previously, attempts were made to deposit Al<sub>2</sub>O<sub>3</sub> by a solution-based methodology<sup>1</sup>, but the observed photocurrents were decreased compared to the system without alumina. Increased dye loading was observed with the addition of the alumina layer in that prior study, although any benefit of increasing the tunneling barrier was counteracted by a reduced injection yield.<sup>1</sup>

Herein, once again we observed significantly increased dye deposition kinetics on the SnO<sub>2</sub>/AlO<sub>x</sub> system. However, the dye deposited onto the SnO<sub>2</sub>/AlO<sub>x</sub> anodes using the same elevated temperature dyeing technique discussed in the main text proved extremely unstable physically; any slight movement or agitation in water immediately resulted in the dye flaking off of the anode. Attempts were made to dye the anodes from room temperature solution over a longer period as well as at elevated temperature for a shorter period; however, in every instance the dye immediately fell off the anodes once removed from solution.

In future studies, the use of a less aggregated<sup>5-9</sup> derivative of the dye could potentially help reduce this preferential binding and stacking of the dye with itself rather than with the SnO<sub>2</sub>/AlO<sub>x</sub>.

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